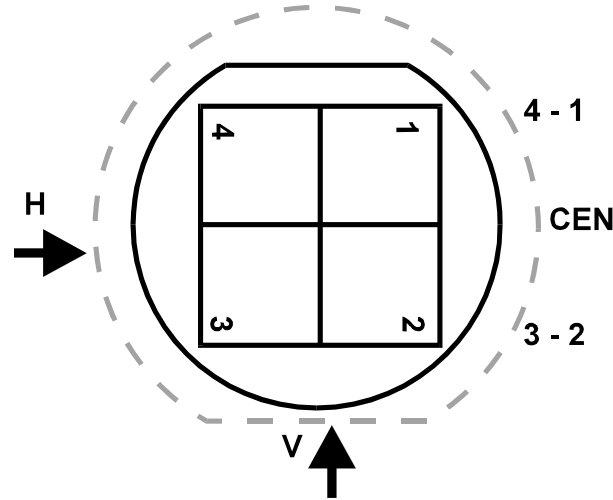


SERVICE CONSORTIUM, INC.

FOCUS DATA SHEET (Vertical Tilt)

Sheet No. _____ of _____
 System No. _____
 Location _____

System S/N _____	Mask: 1 - 4 to front of machine. Wafer: (100mm/125mm) Flat to top of the microscope stage (150m) Flat to bottom of the microscope stage Lines: 1.5 μm <input type="checkbox"/> 2.0 μm <input type="checkbox"/> 3.0 μm <input type="checkbox"/>		
Chuck S/N _____			
Date _____			
Time _____			
Mask S/N _____			
Inlet Air Temp _____			
Reader _____			
Flat <input type="checkbox"/> Wedge <input type="checkbox"/> Exposure/Apt _____			
Opcode 11			
Parameter	S	H	V
Current			
New			



Opcode 11
second parameter adjustment

Correction Factor - C.F. (example)

$C.F. = \frac{12 \mu m}{5 cm} = -A \frac{\mu m}{cm} = -2.4$

ASTIGMATISM

For each micron of astigmatism:

Kamen Gauge
 Move LZ pos 17 microns
 Move RZ neg 17 microns

-003 System
 Rotate Mic 1 cw 7.5
 Rotate Mic 3 ccw 7.5

4-1

→ H
 ↑ V

Outside Focus (away from gauge head)

17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17				

C

→ H
 ↑ V

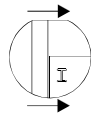
Inside Focus (towards gauge head)

17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17				

3-2

→ H
 ↑ V

17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17				



2 μm shift per box

